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D. Sriram, R. Joobbani
April 1985 **ACM SIGART Bulletin**, Issue 92
Publisher: ACM Press
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The papers in this special issue were compiled from responses to the announcement in the July 1984 issue of the SIGART newsletter and notices posted over the ARPAnet. The interest being shown in this area is reflected in the sixty papers received from over six countries. About half the papers were received over the computer network.

2   System-level power optimization: techniques and tools
Luca Benini, Giovanni de Micheli
April 2000 **ACM Transactions on Design Automation of Electronic Systems (TODAES)**, Volume 5 Issue 2
Publisher: ACM Press
Full text available: 🗎 pdf(385.22 KB)   Additional Information: full citation, abstract, references, citings, index terms

This tutorial surveys design methods for energy-efficient system-level design. We consider electronic sytems consisting of a hardware platform and software layers. We consider the three major constituents of hardware that consume energy, namely computation, communication, and storage units, and we review methods of reducing their energy consumption. We also study models for analyzing the energy cost of software, and methods for energy-efficient software design and compilation. This survery ...

3   Testing and Debugging Custom Integrated Circuits
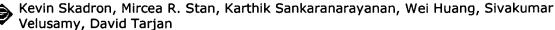Edward H. Frank, Robert F. Sproull
December 1981 **ACM Computing Surveys (CSUR)**, Volume 13 Issue 4
Publisher: ACM Press
Full text available: 🗎 pdf(2.25 MB)   Additional Information: full citation, references, citings, index terms

4   Temperature-aware microarchitecture: Modeling and implementation
Kevin Skadron, Mircea R. Stan, Karthik Sankaranarayanan, Wei Huang, Sivakumar Velusamy, David Tarjan
March 2004 **ACM Transactions on Architecture and Code Optimization (TACO)**, Volume 1 Issue 1
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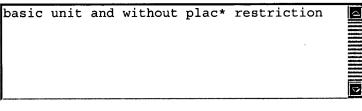
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L1	8	(replicat$3 or duplicat$3) adj3 (cell or gate or circuit or logic) near (critical adj3 path)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 17:14
L2	6	(replicat$3 or duplicat$3) near (cell or gate or circuit or logic) near (critical adj3 path)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 17:21
L3	77	(replicat$3 or duplicat$3) near (cell or gate or circuit or logic) near delay	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 17:20
L4	9034	critical adj3 path	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 17:18
L5	2	3 and 4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/17 17:18